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U.S. PATENT DOCUMENTS											
*EXAMINER			DOCUMENT NUMBER	DATE		NAME	CLASS	SUBCLASS	FILING DAT		
Mo	A1	5,6	13,861	03/25/1997	Smith et	al.	439	81	06/07/19		
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OTHER DOCUMENTS (Including Author, Title, Date, Pertinent Pages, Etc.)											
M		A2	Donald L. Smith et al., "Flip-Chip Bonding on 6-um Pitch using Thin-Film Microspring Technology," Proceedings of the 48th Electronic Components and Technology Conference; Seattle, Washington; May 1998; copyright 1998 IEEE; 3 pages								
M	Soonil Hong et al., "DESIGN AND FABRICATION OF A MONOLITHIC HIGH-DENSITY PROBE CARD FOR HIGH-FREQUENCY ON-WATER TESTING," IEDM 89, pp. 289-292 (4 pages) (no month)										
EXAMINER	1		Winh	/		DATE CONSIDERED 12	/18/03	,			
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OTHER DOCUMENTS (Including Author, Title, Date, Pertinent Pages, Etc.)												
2 2		Bi	Yanwei Zhang et al.; "A	NEW MEMS WA	FER PR	OBE CARD," 0-7803-3	744-1/97 IEEE					
Nh			(no month)									
N6		B2	Shinichiro Asai et al.; "Probe Card with Probe Pins Grown by the Vapor-Liquid-Solid(VLS) Method;" IEEE Transactions on Components, PACKAGING AND MANUFACTURING TECHBNOLOGY-Part A, Vol. 19, No. 2, June 1996; pp. 258-267 (10 pages)									
EXAMINER	₹		Winh			DATE CONSIDERED	12/18/03	}				
			erence considered, whether			ance with MPEP 609; Dra	w line through o	itation if not in c	onformance	and not		

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		REF DOCUMENT NUMBER		DATE		COUNTRY	CLASS	SUBCLASS	YES	NO		
M	б	Al	2000)-317900A	11/21/2000	Japan						
		A2	9-12	6833A	05/16/1997	Japan						
		A3	2000)-65852A _#	03/03/2000	Japan				· · · · · · · · · · · · · · · · · · ·		
		A4	1-12	8381A	05/22/1989	Japan						
\mathcal{N}	D	A5	11-1	60355A	06/18/1999	Japan						
	<u> </u>					OTHER	DOCUMENTS (Including	Author, Title, D	ate, Pertinent Pa	ges, Etc.)		
	Seiichi HATA, et al; "Hakamaky Kinzoku Glass wo mochiita Bisai Kouzoubutsu no Seisaku (Dai 1 Hou)"; Seimitsu											
1	Kougakkaishi, January 2000, Vol. 66, No. 1, pp. 96-101											
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U.S. PATENT DOCUMENTS											
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	DOCUMENT NUMBER		DATE		COUNTRY	CLASS	SUBCLASS	TRANS YES	NO NO		
Mo	Bı	2000-74941A	03/14/2000	Japan							
	B2	9-196970A	07/31/1997	Japan							
	В3	6-308158A1	11/04/1994	Japan							
	B4	5-251523A	09/28/1993	Japan							
No	B5	5-309427A	11/04/1993	Japan							
OTHER DOCUMENTS (Including Author, Title, Date, Pertinent Pages, Etc.)											
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